

Single Molecular Resonant-Tunneling Transistor (SMRT²) based on Quinoidal Fused Oligosilole Derivative (Si-2*2) bridged between H-ELGP Pt-based Nanogap Electrodes

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Nowadays, many researchers have proposed the next-generation transistors toward 3nm technology node to obtain a good on/off ratio. We have reported single molecular resonant tunneling transistor (SMRT²) operation based on rigid π -conjugated molecule and hemispheric electroless Au plated (H-ELGP) Pt-based nanogap electrodes. Here, we introduce Si-bridged quinoidal fused oligosilole derivative (Si-2*2) which has a 34 π -conjugated molecular structure with four silicon atoms depicted in **Figure 1**. Si-2*2 is a strong candidate of functional group for molecular transistors due to structural stability for change in the valence charge.

Si-2*2 was bridged between hemispheric electroless Au-plated (H-ELGP) nanogap Pt electrodes through thiol groups at the both ends. Gate voltage dependence of I_d - V_d characteristics are shown in **Figure 2**. I_d - V_d characteristics are symmetrical to the $V_d = 0$, extremely high current, and clearly depended on gate voltage. These results indicate the operations of the bridged single molecular resonant tunneling transistor.

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[1] R. Shintani *et al.*, *J. Am. Chem. Soc.*, **139**, 3861 (2017).

[2] O. Chun *et al.*, *ACS Omega* **3**, 5125-5130 (2018)

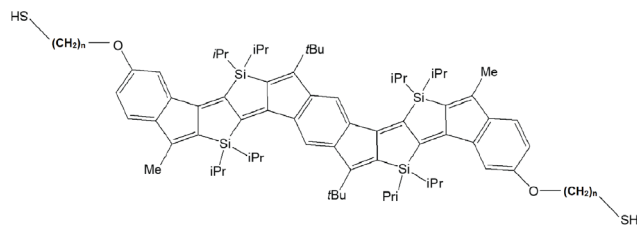


Fig 1. Molecular structure of Si-2*2

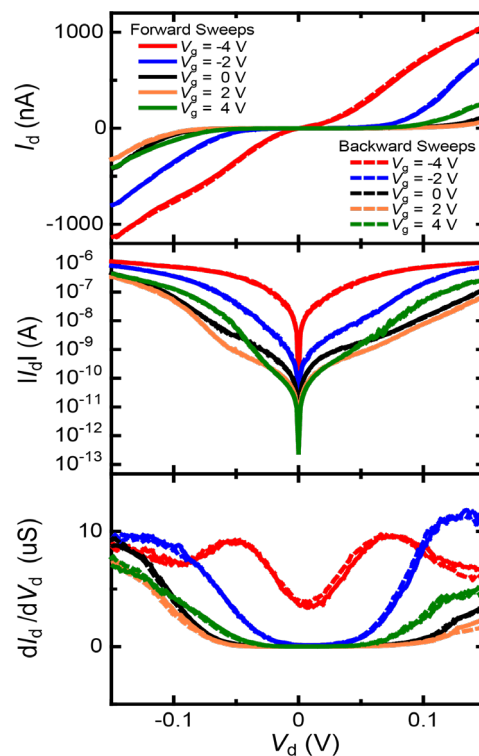


Fig 2. Gate voltage dependence of I_d - V_d and dI_d/dV_d - V_d characteristics of Si-2*2 SMRT² measured under the 9K.